

Analysis of Data-Leak Hardware Trojans In AES Cryptographic Circuits

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Brief Overview

This study explored the impact of 18 Trojans:

- ▶ All Trojans leaked sensitive information
- ▶ All Trojans were implemented on the same circuit

The Trojans explored in this study were found to have:

- ▶ Very small footprints
- ▶ No fixed cost
 - ▶ Widely varies even for similar Trojans
- ▶ A cost dependent upon designer, not Trojan



“The concept of trust requires an accepted dependence or reliance upon another component or system”¹

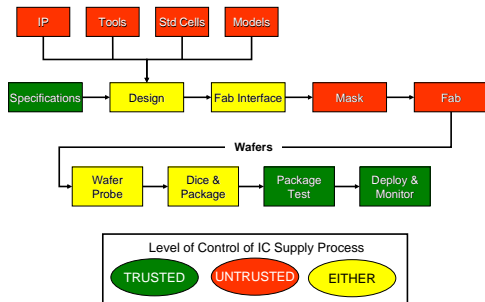


Figure (1). How trusted are steps in circuit production?²

¹ C. E. Irvine and K. Levitt, “Trusted hardware: Can it be trustworthy?” in *44th ACM/IEEE Design Automation Conference (DAC '07)*, 2007, pp. 1–4

² D. Collins, “DARPA Trust in IC’s Effort (BRIEFING CHARTS),” 2007

Can we trust Fabrication Plants?

Table (1). 2011 Top-10 Semiconductor Foundries ³

Rank	Foundry	Location	Sales (USD)
1	TSMC	Taiwan	14,600M
2	UMC	Taiwan	3,760M
3	GlobalFoundries	U.S.	3,580M
4	Samsung	South Korea	1,975M
5	SMIC	China	1,315M
6	TowerJazz	Israel	610M
7	Vanguard	Taiwan	519M
8	Dongbu	South Korea	500M
9	IBM	U.S.	445M
10	MagnaChip	South Korea	350M

³Semiconductor and Manufacturing Design Community,
<http://semimd.com/blog/2012/02/10/umc-seeks-to-shed-image-as-'fast-follower'/>



Hardware Trojans

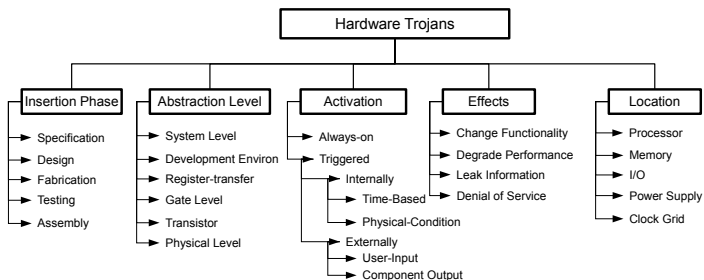


Figure (2). Sample Hardware Trojan Taxonomy⁴

There are **many** possible ways to maliciously influence a circuit

⁴R. Karri, J. Rajendran, K. Rosenfeld, and M. Tehranipoor, "Trustworthy hardware: Identifying and classifying hardware trojans," *Computer*, vol. 43, no. 10, pp. 39–46, 2010



Finding a Solution

How to mitigate Trojans inserted during fabrication:

- ▶ Prevent Trojan insertion
 - ▶ Circuit Hardening
 - ▶ Circuit Obfuscation
- ▶ Secure the fabrication step
 - ▶ Fabricate in-house
 - ▶ Rely on trusted Fabs
- ▶ Detect Trojan presence
 - ▶ Reverse Engineering
 - ▶ Exhaustive Testing
 - ▶ Side-Channel measurements



Side-Channel Techniques

Detection of Trojans through changes to secondary measurements such as:

- ▶ power consumption
- ▶ critical path timing
- ▶ light emission
- ▶ electromagnetic measurements

These techniques rely on a Trojan having a large impact.

- ▶ What are the limits of their effectiveness?
- ▶ How much can they detect?
- ▶ *What is the smallest Trojan they can detect?*



Process Variation

The largest obstacle to detection: Process Variation.

- ▶ Timing measurements are unreliable
- ▶ Leakage current varies by 5-10 times
- ▶ Total power varies by up to 50%⁵

What can we detect?

Where do we draw the line?

⁵S. Borkar, "Designing reliable systems from unreliable components: the challenges of transistor variability and degradation," *IEEE Micro*, vol. 25, no. 6, pp. 10–16, 2005



Trojan Size

Some example Trojans have shown to be very small

- ▶ Even as low as 0.1% of total gate count in a LEON3 Processor⁶
- ▶ Around 0.1% to 0.4% increase in power/area in a MC-8051 microcontroller⁷

However, each Trojan affects each circuit differently.

- ▶ What is the cost (in area/power) to implement a Trojan?
- ▶ Is there a minimum cost?

⁶S. T. King, J. Tucek, A. Cozzie, C. Grier, W. Jiang, and Y. Zhou, "Designing and implementing malicious hardware," in *Proceedings of the 1st Usenix Workshop on Large-Scale Exploits and Emergent Threats (LEET '08)*, 2008

⁷T. Reece, D. Limbrick, X. Wang, B. Kiddie, and W. Robinson, "Stealth assessment of hardware trojans in a microcontroller," in *IEEE 30th International Conference on Computer Design (ICCD '12)*, 2012-Oct. 3, pp. 139–142

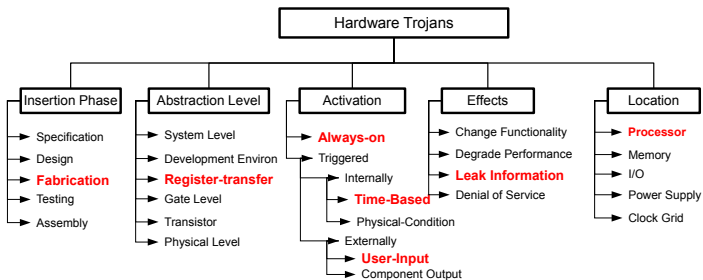


Table (2). Trust-HUB Trojans on a 128-bit AES circuit

Trojan #	Trigger/Payload
AES-T100	<i>Always leak key covertly over many clock cycles</i>
AES-T200	<i>Always leak key covertly over many clock cycles</i>
AES-T300	<i>Leak parts of key intermittently</i>
AES-T400	<i>Always leaks key over RF</i>
AES-T500	<i>Drains the battery over time (not tested)</i>
AES-T600	<i>Always leak key covertly through leakage current</i>
AES-T700	<i>Leaks key after detecting specific sequence</i>
AES-T800	<i>Leaks key after detecting specific sequence</i>
AES-T900	<i>Leaks key after set number of clock cycles</i>
AES-T1000	<i>Leaks key after detecting specific sequence</i>
AES-T1100	<i>Leaks key after detecting specific sequence</i>
AES-T1200	<i>Leaks key after set number of clock cycles</i>
AES-T1300	<i>Leaks key after detecting specific sequence</i>
AES-T1400	<i>Leaks key after detecting specific sequence</i>
AES-T1500	<i>Leaks key after set number of clock cycles</i>
AES-T1600	<i>Always leaks key over RF</i>
AES-T1700	<i>Always leaks key over RF</i>
AES-T1800	<i>Drains the battery over time (not tested)</i>
AES-T1900	<i>Drains the battery over time (not tested)</i>
AES-T2000	<i>Leaks key after detecting specific sequence</i>
AES-T2100	<i>Leaks key after set number of encryptions</i>



Hardware Trojans



Understanding the Implementation Cost of Trojans

Trust-HUB Trojan 128-bit AES cryptographic circuit:

- ▶ 18 different implementations of data-leaks
- ▶ Identical host-circuit

What is the minimum Trojan impact?

Results: There is no meaningful minimum impact



Understanding the Implementation Cost of Trojans

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Methodology

1. Circuits were synthesized to standard cell libraries
2. Trojan circuits were compared to clean circuits to identify:
 - ▶ Changes in area
 - ▶ Differences in leakage power
 - ▶ Differences in dynamic power



Tools

These results were observed with

- ▶ Synopsys Design Compiler
- ▶ Cadence RTL Compiler

When synthesized to

- ▶ Synopsys 90-nm Cell Library
- ▶ OSU 45-nm Cell library



Impact on Area

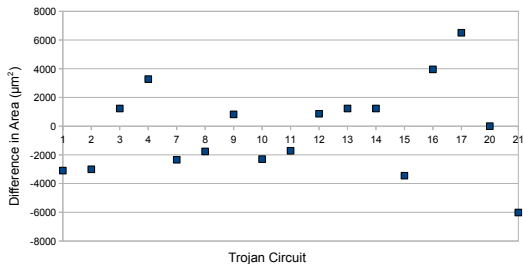


Figure (3). Footprint when synthesized to the Synopsys 90-nm cell library



Impact on Area

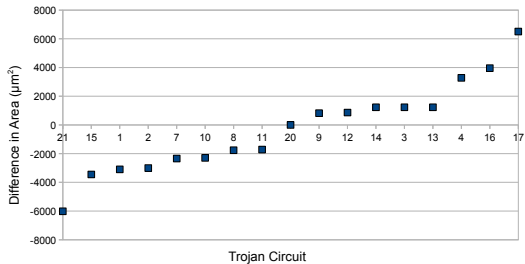


Figure (4). Footprint when synthesized to the Synopsys 90-nm cell library

The impact on area had a very even spread, with no observed “minimum”.



Impact on Area

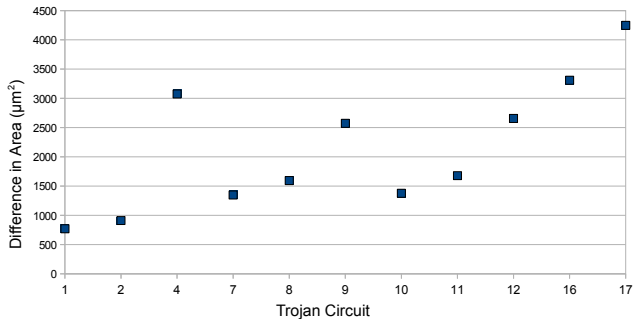


Figure (5). Footprint of Trojan circuits in area (μm^2) when synthesized to the OSU FreePDK 45-nm cell library.



Impact on Leakage Power

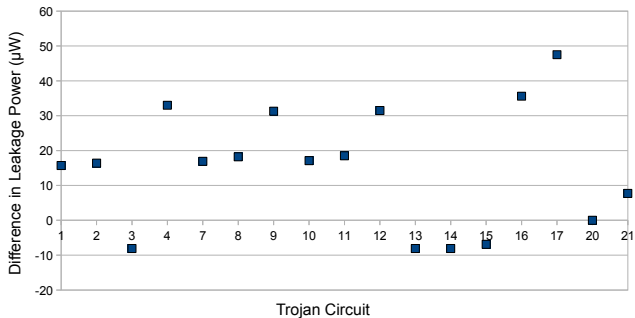


Figure (6). Footprint of Trojan circuits in leakage power (μW) when synthesized to the Synopsys 90-nm library.



Impact on Leakage Power

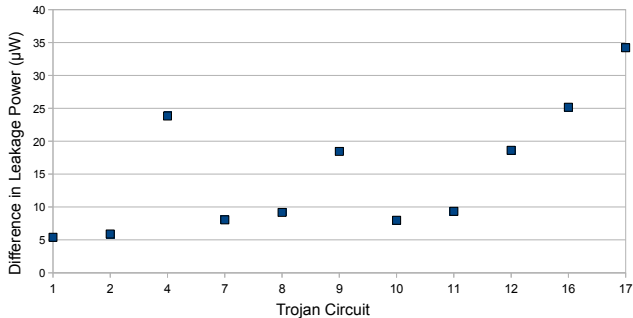


Figure (7). Footprint of Trojan circuits in leakage power (μW) when synthesized to the 45-nm OSU FreePDK cell library.



Impact on Dynamic Power

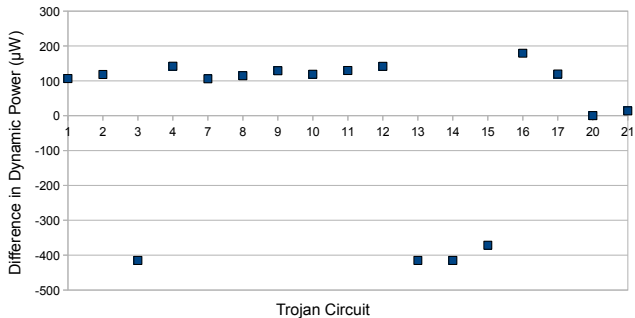


Figure (8). Footprint of Trojan circuits in dynamic power (μW) when synthesized to the Synopsys 90-nm library.



Impact on Dynamic Power

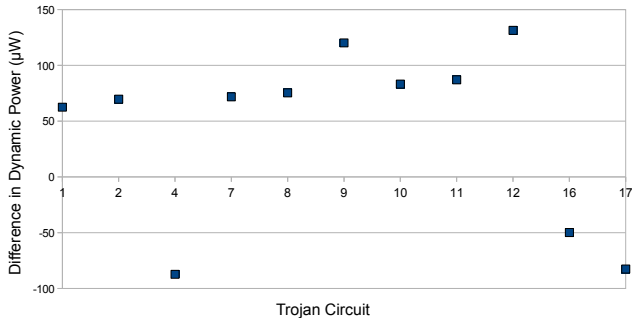


Figure (9). Footprint of Trojan circuits in dynamic power (μW) when synthesized to the 45-nm OSU FreePDK cell library.



Summary of results - 90-nm Library

Area

- ▶ Even spread between $-6,018 \mu m^2$ and $6,506 \mu m^2$
- ▶ +/- 6,000 represents 0.4% of the clean area
- ▶ Absolute average impact was closer to 0.16%

Leakage Power

- ▶ Impact between $6.9 \mu W$ and $47.5 \mu W$
- ▶ Percent impact varied between 0.19% and 1.34%

Dynamic Power

- ▶ Even spread between $13.9 \mu W$ and $415 \mu W$
- ▶ Percent impact varied between 0.2% and 6%



Summary of results - 45-nm Library

Area

- ▶ Impact between $770.1 \mu m^2$ and $4,247 \mu m^2$
- ▶ Percent impact varied between 0.28% and 1.56%

Leakage Power

- ▶ Impact between $5.4 \mu W$ and $34.1 \mu W$
- ▶ Percent impact varied between 0.17% and 1.05%

Dynamic Power

- ▶ Even spread between $49.8 \mu W$ and $131 \mu W$
- ▶ Percent impact varied between 0.29% and 0.77%



Key Findings

There were several key results:

- ▶ Very small footprints
- ▶ No fixed cost
 - ▶ Widely varies even for similar Trojans
- ▶ Cost is dependent upon designer, not Trojan
- ▶ Differences in timing were so small that they could not be distinguished with the granularity of the software.



Questions?





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